

<b>Notice of References Cited</b>	Application/Control No. 09/894,653	Applicant(s)/Patent Under Reexamination DEDU-CONSTANTIN ET AL.	
	Examiner Susan Y. Chen	Art Unit 2161	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0149572	07-2005	Kanai et al.	707/104.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"X-Schema", Mark Birbeck, June 23, 1999, <a href="http://mailman.ic.ac.uk/pipermail/xml-dev/1999-June/013125.html">http://mailman.ic.ac.uk/pipermail/xml-dev/1999-June/013125.html</a>
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.